

## ABSTRACT OF THE DISCLOSURE

A block, which is an object to be scanned, of a semiconductor integrated circuit includes a scan flip-flop and a combinational circuit.

5 A serial-parallel conversion unit receives serial scan output data output from the scan flip-flop of the block and converts the serial scan output data into parallel scan output data. A scan output storage stores the parallel scan output data output from the serial-parallel conversion unit, and outputs the parallel scan output data stored to outside of the semiconductor integrated circuit.